

AP4506GEH

RoHS-compliant Product

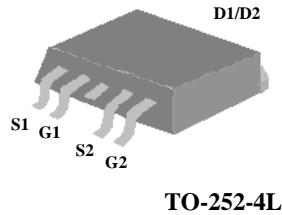


**Advanced Power
Electronics Corp.**

N AND P-CHANNEL ENHANCEMENT

MODE POWER MOSFET

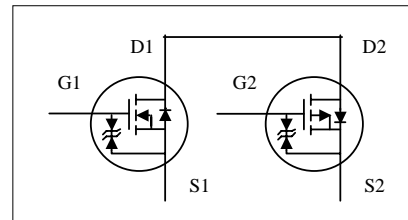
- ▼ Simple Drive Requirement
- ▼ Good Thermal Performance
- ▼ Fast Switching Performance



| | | |
|------|--------------|--------------|
| N-CH | BV_{DSS} | 30V |
| | $R_{DS(ON)}$ | 24m Ω |
| | I_D | 9A |
| P-CH | BV_{DSS} | -30V |
| | $R_{DS(ON)}$ | 36m Ω |
| | I_D | -8A |

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.



Absolute Maximum Ratings

| Symbol | Parameter | Rating | | Units |
|--------------------------|---------------------------------------|------------|-----------|------------|
| | | N-channel | P-channel | |
| V_{DS} | Drain-Source Voltage | 30 | -30 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | ± 20 | V |
| $I_D @ T_A = 25^\circ C$ | Continuous Drain Current ³ | 9 | -8 | A |
| $I_D @ T_A = 70^\circ C$ | Continuous Drain Current ³ | 7.2 | -6.4 | A |
| I_{DM} | Pulsed Drain Current ¹ | 50 | -50 | A |
| $P_D @ T_A = 25^\circ C$ | Total Power Dissipation | 3.1 | | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | | $^\circ C$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | | $^\circ C$ |

Thermal Data

| Symbol | Parameter | Value | Unit |
|--------|---|-------|--------------|
| Rthj-c | Maximum Thermal Resistance, Junction-case | 8 | $^\circ C/W$ |
| Rthj-a | Maximum Thermal Resistance, Junction-ambient ³ | 40 | $^\circ C/W$ |



N-CH Electrical Characteristics @T_j=25°C (unless otherwise specified)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|---------------------|--|--|---|------|------|-------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250uA | 30 | - | - | V |
| R _{DS(ON)} | Static Drain-Source On-Resistance ² | V _{GS} =10V, I _D =6A | - | - | 24 | mΩ |
| | | V _{GS} =4.5V, I _D =4A | - | - | 32 | mΩ |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250uA | 1 | - | 3 | V |
| g _{fs} | Forward Transconductance | V _{DS} =10V, I _D =6A | - | 17 | - | S |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =30V, V _{GS} =0V | - | - | 10 | uA |
| | | Drain-Source Leakage Current (T _j =70°C) | V _{DS} =24V, V _{GS} =0V | - | - | 25 |
| I _{GSS} | Gate-Source Leakage | V _{GS} =±20V, V _{DS} =0V | - | - | ±30 | uA |
| Q _g | Total Gate Charge ² | I _D =6A | - | 8.3 | 13 | nC |
| Q _{gs} | Gate-Source Charge | V _{DS} =24V | - | 1.5 | - | nC |
| Q _{gd} | Gate-Drain ("Miller") Charge | V _{GS} =4.5V | - | 4 | - | nC |
| t _{d(on)} | Turn-on Delay Time ² | V _{DS} =15V | - | 5 | - | ns |
| t _r | Rise Time | I _D =6A | - | 18 | - | ns |
| t _{d(off)} | Turn-off Delay Time | R _G =3.3Ω, V _{GS} =10V | - | 18 | - | ns |
| t _f | Fall Time | R _D =2.5Ω | - | 4 | - | ns |
| C _{iss} | Input Capacitance | V _{GS} =0V | - | 575 | 920 | pF |
| C _{oss} | Output Capacitance | V _{DS} =25V | - | 100 | - | pF |
| C _{rss} | Reverse Transfer Capacitance | f=1.0MHz | - | 70 | - | pF |

Source-Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|-----------------|------------------------------------|---|------|------|------|-------|
| V _{SD} | Forward On Voltage ² | I _S =6A, V _{GS} =0V | - | - | 1.3 | V |
| t _{rr} | Reverse Recovery Time ² | I _S =6A, V _{GS} =0V | - | 19 | - | ns |
| Q _{rr} | Reverse Recovery Charge | dI/dt=100A/μs | - | 14 | - | nC |

**P-CH Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)**

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|--------------|--|--------------------------------|------|------|----------|------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=-250\mu A$ | -30 | - | - | V |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance ² | $V_{GS}=-10V, I_D=-5A$ | - | - | 36 | m Ω |
| | | $V_{GS}=-4.5V, I_D=-3A$ | - | - | 48 | m Ω |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=-250\mu A$ | -1 | - | -3 | V |
| g_{fs} | Forward Transconductance | $V_{DS}=-10V, I_D=-5A$ | - | 12 | - | S |
| I_{DSS} | Drain-Source Leakage Current | $V_{DS}=-30V, V_{GS}=0V$ | - | - | -10 | μA |
| | | $V_{DS}=-24V, V_{GS}=0V$ | - | - | -25 | μA |
| I_{GSS} | Gate-Source Leakage | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 30 | μA |
| Q_g | Total Gate Charge ² | $I_D=-5A$ | - | 12.6 | 20 | nC |
| Q_{gs} | Gate-Source Charge | $V_{DS}=-24V$ | - | 2.4 | - | nC |
| Q_{gd} | Gate-Drain ("Miller") Charge | $V_{GS}=-4.5V$ | - | 6.2 | - | nC |
| $t_{d(on)}$ | Turn-on Delay Time ² | $V_{DS}=-15V$ | - | 8 | - | ns |
| t_r | Rise Time | $I_D=-5A$ | - | 16 | - | ns |
| $t_{d(off)}$ | Turn-off Delay Time | $R_G=3.3\Omega, V_{GS}=-10V$ | - | 26 | - | ns |
| t_f | Fall Time | $R_D=3\Omega$ | - | 41 | - | ns |
| C_{iss} | Input Capacitance | $V_{GS}=0V$ | - | 1045 | 1670 | pF |
| C_{oss} | Output Capacitance | $V_{DS}=-25V$ | - | 220 | - | pF |
| C_{rss} | Reverse Transfer Capacitance | $f=1.0\text{MHz}$ | - | 150 | - | pF |

Source-Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|----------|------------------------------------|----------------------|------|------|------|-------|
| V_{SD} | Forward On Voltage ² | $I_S=-5A, V_{GS}=0V$ | - | - | -1.3 | V |
| t_{rr} | Reverse Recovery Time ² | $I_S=-5A, V_{GS}=0V$ | - | 23 | - | ns |
| Q_{rr} | Reverse Recovery Charge | $di/dt=-100A/\mu s$ | - | 15 | - | nC |

Notes:

1. Pulse width limited by Max. junction temperature.
2. Pulse test
3. N-CH, P-CH are same, mounted on 2oz FR4 board $t \leq 10s$.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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N-Channel

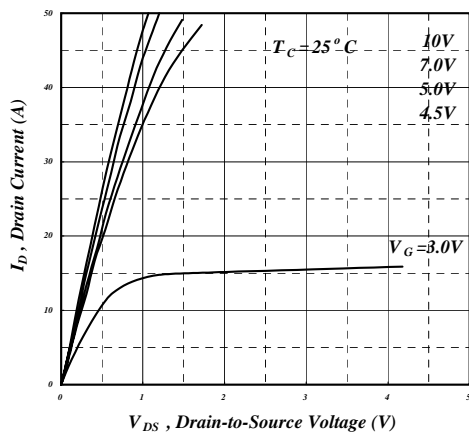


Fig 1. Typical Output Characteristics

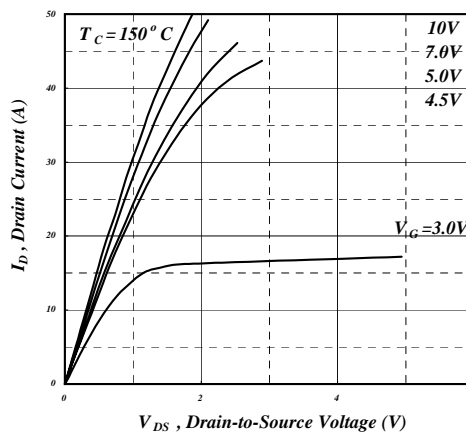


Fig 2. Typical Output Characteristics

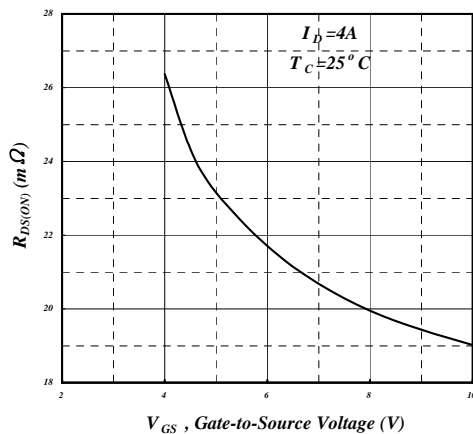


Fig 3. On-Resistance v.s. Gate Voltage

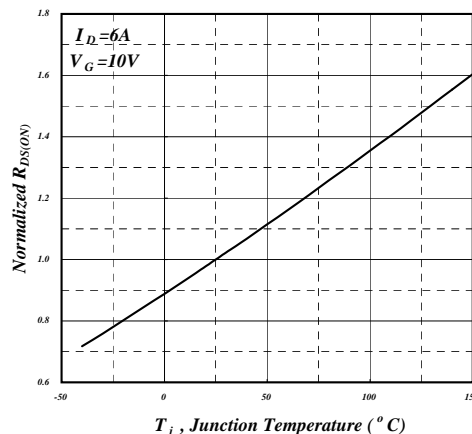


Fig 4. Normalized On-Resistance v.s. Junction Temperature

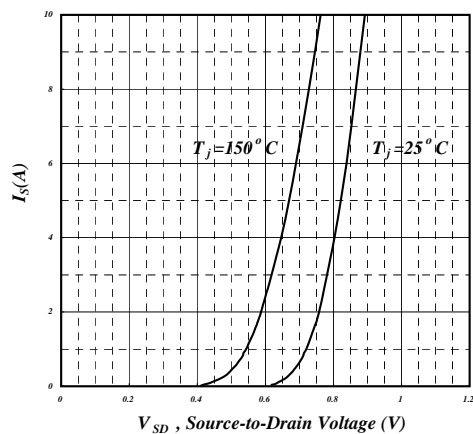


Fig 5. Forward Characteristic of Reverse Diode

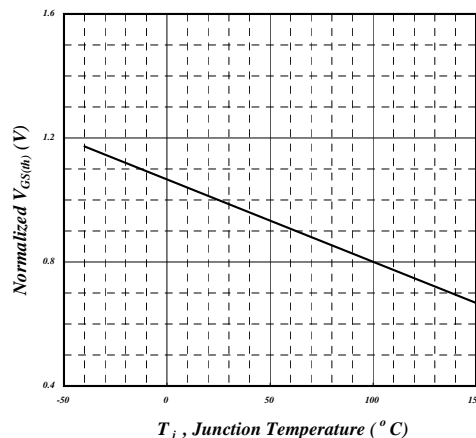


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



N-Channel

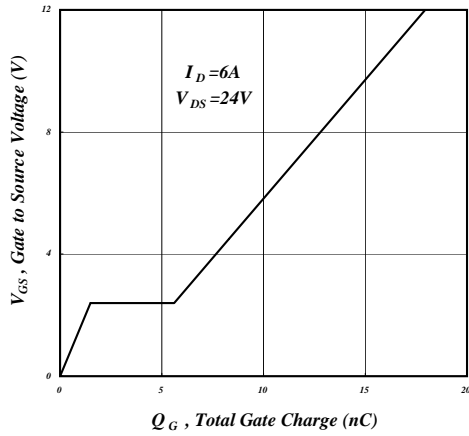


Fig 7. Gate Charge Characteristics

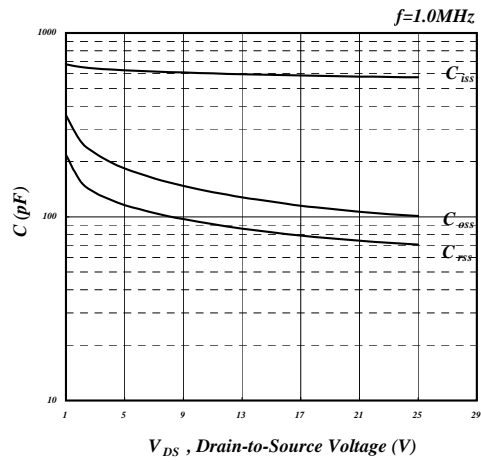


Fig 8. Typical Capacitance Characteristics

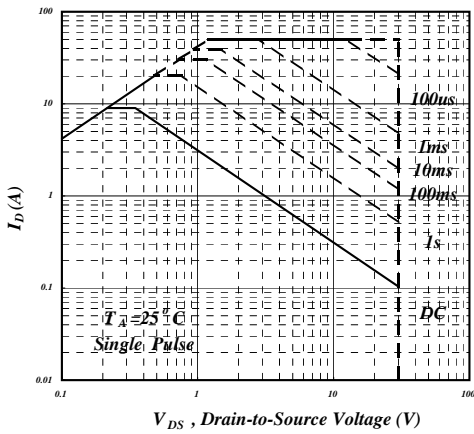


Fig 9. Maximum Safe Operating Area

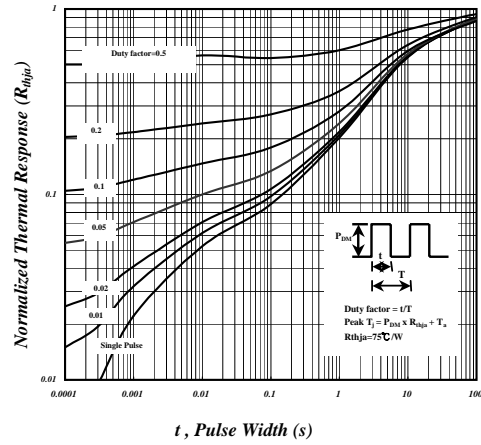


Fig 10. Effective Transient Thermal Impedance

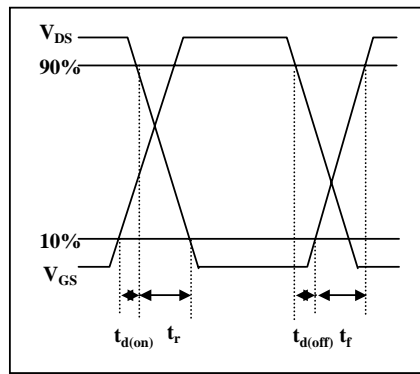


Fig 11. Switching Time Waveform

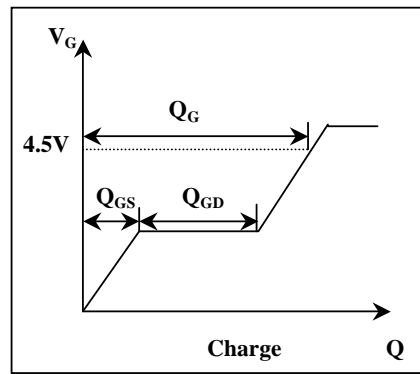


Fig 12. Gate Charge Waveform



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P-Channel

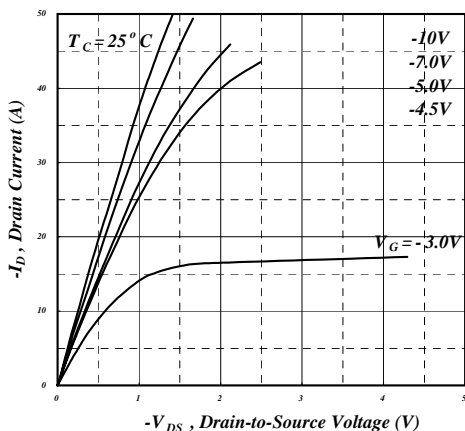


Fig 1. Typical Output Characteristics

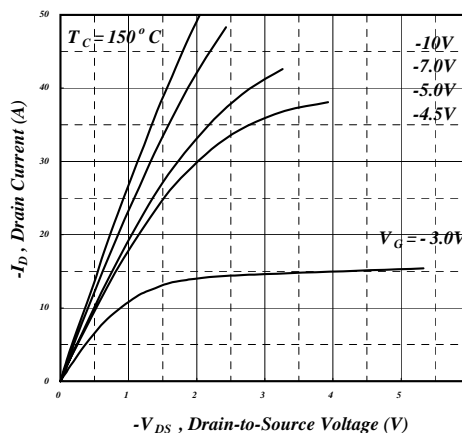


Fig 2. Typical Output Characteristics

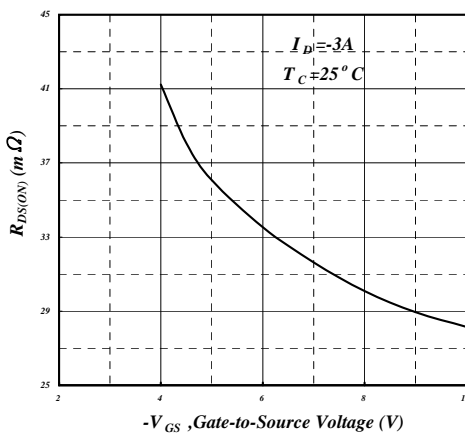


Fig 3. On-Resistance v.s. Gate Voltage

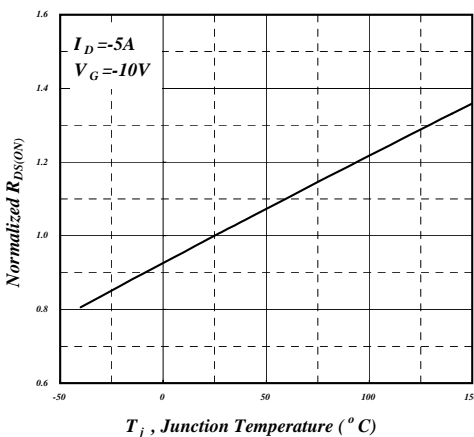


Fig 4. Normalized On-Resistance v.s. Junction Temperature

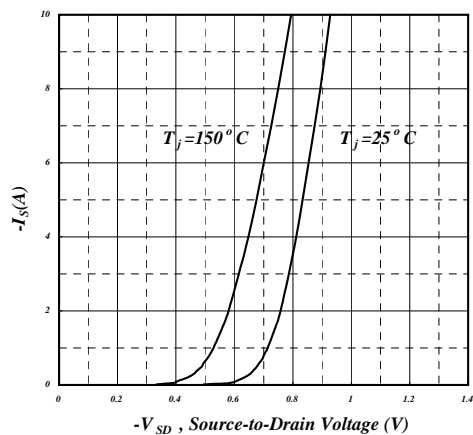


Fig 5. Forward Characteristic of Reverse Diode

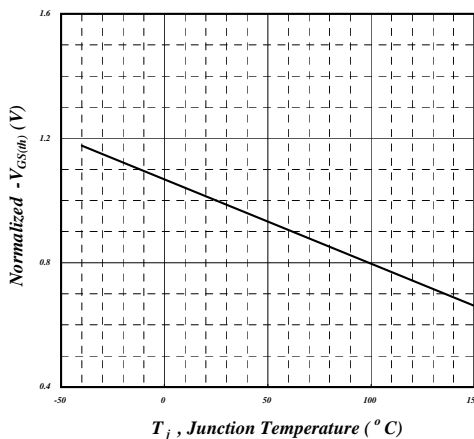


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



P-Channel

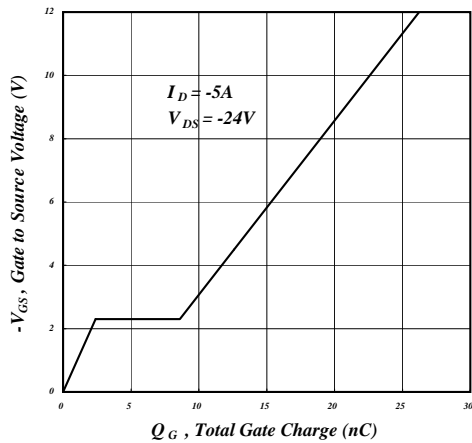


Fig 7. Gate Charge Characteristics

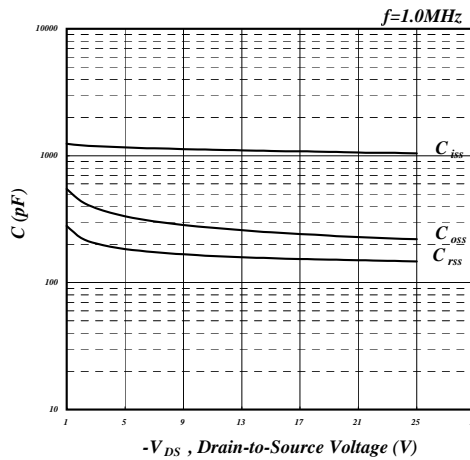


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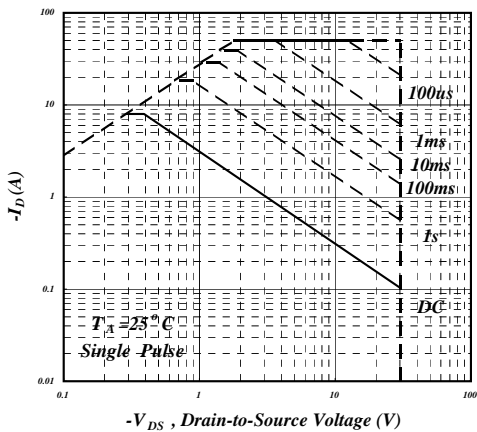


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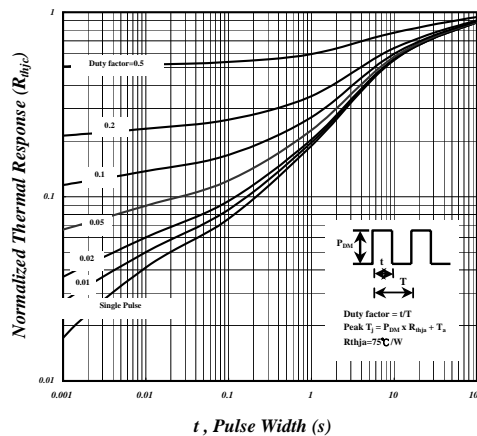


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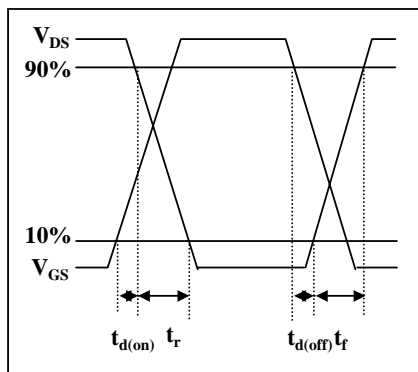


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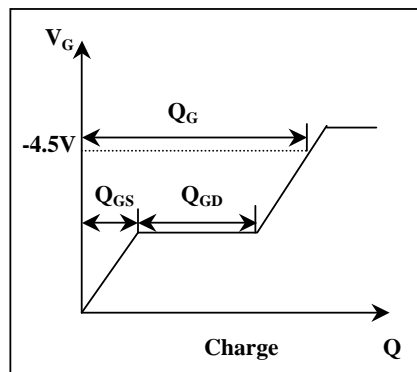


Fig 12. Gate Charge Waveform